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18th July 2022

PCN-01565

Digi-Key Corporation 701 Brooks Ave South Thief River Falls, Minnesota 56701

Subject: Additional testing and packaging site.

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

Sincerely

Tom Galluccio Director, Product Marketing thomas.galluccio@macom.com



Appendix I Affected part numbers

Part Number	Part Type
MX51359-11	Diode
MMP7033-11	Diode
MX52087-11	Diode
MX52077-11	Diode
MMP7026-11	Diode
M5X3026	Diode
SMV20415-11	Diode
MX51985-11	Diode
M5X3874	Diode
MA4P504-132	Diode
MA4P404-132	Diode
MA46472-134	Diode
MA4P606-131	Diode
MA46600-134	Diode
MX50086-11	Diode
MX51735-11	Diode
MMP7066-11	Diode
MMP7022-11	Diode
MX50419-11	Diode
M5X1422	Diode
MX50362-11	Diode
MX1436	Diode
MX51812-11	Diode
MX51630-11	Diode
MX51911-11	Diode
MX51749-11	Diode
MA4AGSW1	Diode
MA4AGSW2	Diode
9147RM	Capacitor
MX52271	Capacitor
M3X3028	Capacitor
MA4M3100	Capacitor
MA4M3050	Capacitor
9112RK	Capacitor



901R5K-SP	Capacitor
M3X1523	Capacitor
90R75K-SP	Capacitor
9020RK	Capacitor
M3X1975	Capacitor
914R0K	Capacitor
90R6K-SP	Capacitor
90R4K-SP	Capacitor
90100RK	Capacitor
9010RK	Capacitor

Appendix II The new testing and assembly facility









Appendix III Qualification process capability data

Two representative part numbers (MX51267-11 and MC2S022025-025) are tested and qualified in Year 2000 as below, and the rest parts in the pcn can be qualified by similarity to the representative parts as they have the same production process.

1. Diode.

MX51267-11

Test conditions: IR1max=10uA, under -1100V.

IR2max=0.05uA, under -1000V.

Cj1max=0.25pF, under -28V.

VF1max=1.25V, under 100mA.

Sample size=100,10 sub-groups.

IR1:





IR2:



The actual process spread is represented by 6 sigma.





The actual process spread is represented by 6 sigma.



VF1:





2. Capacitor.

MC2S022025-025

Test conditions: Cj1min=18pF, Cj1max=26pF, under 0V.

VBmin=50V, under -10uA.

Sample size=100,10 sub-groups.

CJ1:



The actual process spread is represented by 6 sigma.



VB:





Appendix IV Qualification Gage R&R testing data

1. Diode test parameters

Specification:-			
a) GR&R Contribution % ≦10%			
b) GR&R Varia	tion % ≦30%		
	GR&R	GR&R	Result
Parameter	Contribution %	Variation%	Result
	GR&R	GR&R	
IR1	0.21	4.57	PASS
	6.62	25.72	PASS
IR2			
IR2 Cj1	1.13	10.65	PASS



Gage R&R (ANOVA) Report for IR2





Gage R&R (ANOVA) Report for Cj1



Gage R&R (ANOVA) Report for VF1

Components of Variation



2. Capacitor test parameters

GR&R summary:

Specification:-			
a) GR&R Contr	ibution % ≦10%		
b) GR&R Varia	tion % ≦30%		
Parameter	GR&R Contribution % GR&R	GR&R Variation% GR&R	Result
VB	5.69	23.85	PASS
VB	5.05	20.00	

Gage R&R (ANOVA) Report for Vb





Gage R&R (ANOVA) Report for Cj1

